

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims**

**Claim 1 (Currently Amended):** A method for patterning a layer of a low dielectric constant material, comprising:

applying a surface imaging material having silicon incorporated therein on a layer of a low dielectric constant material, the surface imaging material having a thickness in the range from about 500 angstroms to about 2,500 angstroms;

defining a pattern in the surface imaging material;

hardening the patterned surface imaging material so that the patterned surface imaging material functions as a hard mask; and

transferring the pattern defined in the surface imaging material to the layer of the low dielectric constant material after the patterned surface imaging material is hardened,

wherein the surface imaging material is incorporated with silicon without a separate silylation operation, and the hardening of the patterned surface imaging material includes exposing the patterned surface imaging material to an oxygen containing plasma.

**Claim 2 (Original):** The method of claim 1, wherein the low dielectric constant material is selected from the group consisting of doped oxides, organic materials, and nanoporous materials.

**Claim 3 (Original):** The method of claim 1, wherein the low dielectric constant material is a low dielectric constant polymeric material having a dielectric constant below about 3.0.

**Claims 4 and 5 (Canceled).**

**Claim 6 (Currently Amended):** A method for forming an integrated circuit, comprising:

forming a layer of a low dielectric constant material on a substrate;

applying a surface imaging material having silicon incorporated therein on the layer of the low dielectric constant material, the surface imaging material having a thickness in the range from about 500 angstroms to about 2,500 angstroms;

defining a pattern in the surface imaging material;

hardening the patterned surface imaging material so that the patterned surface imaging material functions as a hard mask; and

transferring the pattern defined in the surface imaging material to the layer of the low dielectric constant material after the patterned surface imaging material is hardened,

wherein the surface imaging material is incorporated with silicon without a separate silylation operation, and the hardening of the patterned surface imaging material includes exposing the patterned surface imaging material to an oxygen containing plasma.

**Claim 7 (Original):** The method of claim 6, wherein the layer of low dielectric constant material has a thickness in the range from about 3,000 angstroms to about 10,000 angstroms.

**Claim 8 (Original):** The method of claim 6, wherein the substrate is a layer of metal coated with a diffusion barrier.

**Claim 9 and 10 (Canceled).**

**Claim 11 (Original):** The method of claim 8, wherein the layer of the low dielectric constant material forms a first dielectric layer, the pattern transferred to the first dielectric layer defines a via therein, and the method further comprises:

forming a second dielectric layer over the surface imaging material applied on the first dielectric layer, the second dielectric layer being formed of a low dielectric constant material;

applying the surface imaging material on the second dielectric layer;

defining a trench pattern in the surface imaging material applied on the second dielectric layer;

hardening the patterned surface imaging material applied on the second dielectric layer so that the patterned surface imaging material applied on the second dielectric layer functions as a hardmask; and

transferring the trench pattern defined in the surface imaging material applied on the second dielectric layer to the second dielectric layer in the same process used to transfer the via pattern to the first dielectric layer.

**Claim 12 (Original):** The method of claim 6, wherein the low dielectric constant material is selected from the group consisting of doped oxides, organic materials, and nanoporous materials.

**Claim 13 (Original):** The method of claim 6, wherein the low dielectric constant material is a low dielectric constant polymeric material having a dielectric constant below about 3.0.

**Claims 14 and 15 (Canceled).**

**Claim 16 (Currently Amended):** A method for patterning a layer of a low dielectric constant polymeric material, comprising:

applying a surface imaging material having silicon incorporated therein on a layer of a low dielectric constant polymeric material, the surface imaging material having a thickness in the range from about 500 angstroms to about 2,500 angstroms;

defining a pattern in the surface imaging material;

hardening the patterned surface imaging material so that the patterned surface imaging material functions as a hard mask; and

transferring the pattern defined in the surface imaging material to the layer of the low dielectric constant polymeric material after the patterned surface imaging material is hardened.

wherein the surface imaging material is incorporated with silicon without a separate silylation operation, and the hardening of the patterned surface imaging material includes exposing the patterned surface imaging material to an oxygen containing plasma.

**Claim 17 (Original):** The method of claim 16, wherein the low dielectric constant polymeric material has a dielectric constant below about 3.0.

**Claims 18 and 19 (Canceled).**

**Claim 20 (Currently Amended):** A method for patterning a layer of a low dielectric constant material, comprising:

applying a surface imaging material having silicon incorporated therein on a layer of a low dielectric constant material;

defining a pattern in the surface imaging material;

hardening the patterned surface imaging material so that the patterned surface imaging material functions as a hard mask; and

transferring the pattern defined in the surface imaging material to the layer of the low dielectric constant material after the patterned surface imaging material is hardened,

wherein the surface imaging material is incorporated with silicon without a separate silylation operation, and the hardening of the patterned surface imaging material includes exposing the patterned surface imaging material to an oxygen containing plasma.

**Claim 21 (Original):** The method of claim 20, wherein the low dielectric constant material is selected from the group consisting of doped oxides, organic materials, and nanoporous materials.

**Claim 22 (Original):** The method of claim 20, wherein the low dielectric constant material is a low dielectric constant polymeric material having a dielectric constant below about 3.0.

**Claims 23-26 (Canceled).**